

Search Notes				Application/Control No.	Applicant(s)/Patent under Reexamination	
				10/086,262	CHANG ET AL.	
				Examiner	Art Unit	
				Steven HD Nguyen	2665	
SEARCHED				SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
Class	Subclass	Date	Examiner		DATE	EXMR
370	351-356, 401	1/31/2006	ST	<i>See East</i>	9/11/06	<i>8</i>
379	265.02					
	88.17					
	900					
	142.07					
	210.01					
	225, 231					
	265.09					
INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
<i>See East</i>	9/11/06					